

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/036,527	TERANOSHITA, MASAHIKE	
		Examiner	Art Unit	Page 1 of 1
		Thierry L. Pham	2624	

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	E	US-			
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	L	US-			
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**NON-PATENT DOCUMENTS**

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